Introduction

This application note will demystify some important jitter units used in quantifying clock jitter for high-speed applications. While the voltage and current parameters of a clock device are well understood, the units of timing jitter can lead to confusion. This is because there is no universally accepted definition of jitter for all applications.

Jitter can have units in the time and frequency domains; sometimes peak-to-peak values are stated, while other times RMS jitter is given. When datasheets for competing timing products use different units, it can prove challenging to do side-by-side performance comparisons.

This note will focus on the most common jitter units used today and describe the relationships between them. Much of the math and equations have been simplified. This note will focus on the reader’s ability to:

• Compare the jitter performance of various timing products even when different units are used (e.g. RMS jitter versus peak-to-peak jitter).
• Relate the datasheet jitter parameters for a clock generator or transceiver to the application jitter specification (e.g. PCIe Gen3, Gigabit Ethernet etc).
• Appreciate the relationship between jitter and phase noise.

What is Jitter and Phase Noise?

Phase noise and jitter are different ways of quantifying the same phenomenon: signal timing error. In the time domain, common jitter measurements are period jitter, cycle-to-cycle jitter and accumulated jitter. Among these types of jitter, period jitter (see Figure 1 below) is generally given in datasheets.

In the frequency domain, oscillator quality is characterized by phase noise measurements which examine the spectrum of side-band noise frequencies in a clock signal. To keep things simple, assume that the ideal clock is a perfect sine wave with a frequency $F_C$. Such a pure clock will have all its power concentrated at $F_C$ (see Figure 2). The effect of phase noise is to spread the power into sidebands causing slight variations in frequency. So that instead of the oscillator always producing a pure clock signal at $F_C$, it is sometimes a bit faster: $F_C + \Delta f$, or sometimes a bit slower: $F_C - \Delta f$ (see Figure 3). These small changes in clock speed translate into jitter in the time domain.

Various random and deterministic noise sources in an electrical system cause jitter. For an excellent explanation of the types and components of jitter, please refer to the white paper IDT_Jitter-Timing_WHP_20080901. This guide will focus on explaining those unusual jitter and phase noise units seen in high performance timing specifications.
Figure 1. Jitter in the Time Domain

**Ideal Clock:**
Period $T$ is always the same
E.g., $T = 10\text{ns}$ always

**Real Clock:**
Period $T$ varies due to jitter
E.g., $T_0 = 10\text{ns}$, $T_1 = 10.1\text{ns}$, $T_2 = 9.9\text{ns}$

Figure 2. Jitter in the Frequency Domain – Phase Noise

**Spectrum of Perfect Clock**

$$V(t) = A \sin(2\pi F_c t)$$
Power concentrated in single infinitely thin line at $F_c$ on graph

**Real-World Clock**

$$V(t) = [A + a(t)] \sin(2\pi F_c t + \Delta \phi(t))$$
$a(t)$ is random variation of signal amplitude
$\Delta \phi(t)$ is random variations of signal phase, usually called *phase noise*. In oscillators $\Delta \phi(t)$ is the dominant contributor to jitter.
Phase noise broadens the signal spectrum.
Figure 3. Vector Representation of Phase Noise

Quantifying Jitter in the Time Domain

Total jitter (TJ) equals the sum of deterministic jitter (DJ) plus random jitter (RJ). Common sources of deterministic jitter are cross-talk and simultaneous outputs switching. The peak-to-peak value of DJ is finite and can be minimized by careful design (e.g. good PCB routing). The effect of DJ is to add an offset to the value of RJ.

Random jitter (usually due to thermal noise and other uncorrelated noise sources) is unpredictable and typically follows a Gaussian or Normal distribution (see Figure 4). It is highly process dependent. Unlike DJ, the peak-to-peak value of RJ is unbounded; the more samples measured, the wider the variation of RJ_{pk-pk} observed (see Figure 5).
**Figure 4. Gaussian Distribution Reveals Random Nature of Period Jitter**

The real world clock signal
Signal period varies: $T_0, T_1, T_2, \ldots$
Momentary clock frequency changes.
Jitter = Deviation of the clock signal
        transitions from the reference $T_0$
Random jitter has Gaussian distribution.

![Oscilloscope screen shot of sampled clock waveform](image)

- $V(t)$
- $T_0$
- $T_1$
- $T_2$

**Figure 5. Random Jitter is Unbounded. The Peak-to-Peak Value of Jitter Depends on the Number of Samples.**

Oscilloscope shots of clock signal with increasing number of samples

10k Samples
100k Samples
1M Samples
10M Samples

The more you sample, the wider period variation you will see. In this example, at 10k samples Jitter$_{pk-pk}$ = 16.2 ps. At 1M samples Jitter$_{pk-pk}$ = 22.1 ps.
Two Ways of Quantifying Random Jitter: RMS and Peak-to-Peak

Period jitter is the short term variation in clock period compared to the average (mean) clock period. If the average or reference period is To (see Figure 1 above), then we take samples of period jitter as T1 - To, T2 - To, T3 - To, .... and so on until we reach 10,000 samples (JEDEC standard JESD65B).

Plotting these jitter samples as a histogram may well result in a Normal distribution (see Figure 6).

Figure 6. Gaussian (Normal) Distribution

Ideally the mean value µ of jitter is zero. Values to the left of µ represent clock periods smaller than the reference period, and values to the right are larger than the reference clock period.

One standard deviation 1σ each side from µ (dark blue) accounts for about 68% of the jitter samples. While ±2σ from µ (medium and dark blue) account for about 95%, and ±3σ (light, medium, and dark blue) account for about 99.7%.

The Normal distribution yields two common jitter specifications:

- **Root Mean Squared** jitter (RJRMS) or the value of one standard deviation σ. Since this value hardly changes as the number of samples increases, it is considered a more meaningful measurement. However it is only valid in pure Gaussian distributions (no deterministic jitter).

- **Peak-to-peak** jitter or the distance from the smallest to the largest measurement on the normal curve. In most circuits this value increases with the number of samples taken (see Figure 5). To arrive at a meaningful value of peak-to-peak jitter, the bit error ratio (BER) also needs to be specified.

How RMS Jitter Relates to Peak-to-Peak Jitter and BER

In Figure 6, we can see that inside a peak-to-peak range of 6σ (± 3σ from the mean) or 6 x RJRMS, about 99.7% of jitter samples are accounted for. To account for 100% of the jitter samples is impossible - the tales of the Gaussian distribution stretch to infinity. What decides that the peak-to-peak jitter is 6 x RJRMS, or 7 x RJRMS, or 12 x RJRMS?

A useful way to accomplish this is based on the bit error ratio (BER) required by the system. It is assumed that any samples that fall outside the peak-to-peak range will cause bit errors. Therefore, if a BER target of 10^-12 is demanded, it is necessary to select a range that will contain the jitter for all except 0.00000000001% of the time.

To convert from RMS jitter to peak-to-peak jitter using this method, simply multiply RJRMS by the value N corresponding to the appropriate BER in Table 1 below:
Table 1: BER and RMS Multiplier N

<table>
<thead>
<tr>
<th>BER</th>
<th>N</th>
</tr>
</thead>
<tbody>
<tr>
<td>10^{-3}</td>
<td>6.18</td>
</tr>
<tr>
<td>10^{-4}</td>
<td>7.438</td>
</tr>
<tr>
<td>10^{-5}</td>
<td>8.53</td>
</tr>
<tr>
<td>10^{-6}</td>
<td>9.507</td>
</tr>
<tr>
<td>10^{-7}</td>
<td>10.399</td>
</tr>
<tr>
<td>10^{-8}</td>
<td>11.224</td>
</tr>
<tr>
<td>10^{-9}</td>
<td>11.996</td>
</tr>
<tr>
<td>10^{-10}</td>
<td>12.723</td>
</tr>
<tr>
<td>10^{-11}</td>
<td>13.412</td>
</tr>
<tr>
<td>10^{-12}</td>
<td>14.069</td>
</tr>
<tr>
<td>10^{-13}</td>
<td>14.698</td>
</tr>
<tr>
<td>10^{-14}</td>
<td>15.301</td>
</tr>
<tr>
<td>10^{-15}</td>
<td>15.883</td>
</tr>
<tr>
<td>10^{-16}</td>
<td>16.444</td>
</tr>
</tbody>
</table>

For example RJ_{RMS} = 4 \text{ps}, and the system BER requirement is 1 \times 10^{-12}, the corresponding peak-to-peak jitter (rounded up) is:

\[ RJ_{pk-pk} = 4 \times 14.069 = 56.4 \text{ps} \]

This figure gives us an idea of the allowable jitter budget. Roughly speaking, if the various random jitter sources in a communication link add up to less than 56.4ps, then the bit errors should be less than 1 \times 10^{-12}.

**Predicted versus Measured Peak-to-Peak Jitter**

Peak-to-peak jitter is often described in two ways:

- It can be calculated as shown previously using the RMS multiplier. This is predicted peak-to-peak jitter based on a defined BER (usually 1 \times 10^{-12}).
- It can be measured using test equipment. In this case the minimum period sampled is subtracted from the maximum period measured. As we have seen before this will depend on how many samples are taken.

The predicted and measured values will not be the same. The measured value will give a feel for the jitter in the system, but is somewhat meaningless in relation to BER. For example, the peak-to-peak jitter measured from 10,000 samples will not tell you the peak-to-peak jitter needed for BER = 1 \times 10^{-12}. You would need at least 1,000,000,000,000 samples to accomplish that! Therefore RJ_{pk-pk} is usually calculated from RJ_{RMS} at a defined BER.

**Quantifying Jitter in the Frequency Domain: Phase Noise**

As mentioned in the introduction, phase noise describes jitter in the frequency domain. Later we will see that, from the phase noise information, we can extract the RMS Phase Jitter value which is often given in datasheets as a measure of quality and spectral purity.
The frequency spectrum plot in Figure 7 is of a real sinusoidal clock with nominal frequency $F_C$ (also called the carrier frequency) plus sideband offset noise frequencies $F_O$. That means, sometimes the clock will have a slightly larger frequency $F_C + F_O$ and sometimes it will have a slightly lower frequency $F_C - F_O$. The small changes in frequency appear as phase shifts in the clock waveform, hence the name phase noise.

The noise power in a 1Hz band at an offset frequency $F_O$ compared to the power of the carrier frequency $F_C$ is called the **dBc Phase Noise** ($\text{dBc} = \text{power in } \text{dB relative to } \text{carrier}$).

$$\text{dBc Phase Noise} = \frac{\text{Power level of a 1Hz band at offset } F_O}{\text{Power level of carrier frequency } F_C}$$

The actual units of Phase Noise are dBc/Hz because the power is normalized to a 1Hz bandwidth.
Constructing a Phase Noise Plot

Referring to Figure 7 above, by sweeping a 1Hz band from the center of the Frequency Spectrum Plot to the right hand end of the frequency axis, the dBc power level can be calculated at each offset $F_O$. The resulting values are then plotted on a Phase Noise plot as shown in Figure 7. Table 2 below highlights the main differences between the Frequency Spectrum and Phase Noise plots. Figure 8 shows a typical oscillator phase noise plot.

Table 2: Differences between Frequency Spectrum and Phase Noise Plots

<table>
<thead>
<tr>
<th>Frequency Spectrum Plot</th>
<th>Phase Noise Plot</th>
</tr>
</thead>
<tbody>
<tr>
<td>Power levels are in absolute units dB</td>
<td>Noise power levels are relative to carrier, calculated in 1Hz bandwidths. Units are dBc/Hz.</td>
</tr>
<tr>
<td>Frequency axis shows all the frequencies in the signal</td>
<td>Frequency axis only shows the offset (sideband) frequencies. For example, if $F_{CARRIER} = 25$MHz, then when the frequency is 25.01MHz: $F_{OFFSET} = 0.01$MHz = 10kHz</td>
</tr>
<tr>
<td>Carrier frequency is the nominal clock frequency</td>
<td>Offset frequency is the modulation rate of the clock (because the clock is frequency modulated by the noise).</td>
</tr>
<tr>
<td></td>
<td>Single side – only one side of the spectrum is plotted. The assumption is that the noise profile is symmetrical.</td>
</tr>
</tbody>
</table>

Figure 8. Phase Noise Plot of a 311MHz Oscillator (from Thomas Fischer TI). Offset (modulation) Frequencies are shown on a Logarithmic Scale.
RMS Phase Jitter

When looking at oscillator phase noise plots, certain sideband frequency ranges are of interest. In telecommunications, the noise power in the range 12kHz to 20MHz is very important for timing performance. Referring to Figure 8 above:

\[
\text{Noise Power (dBc) = Area under curve from 12kHz to 20MHz = -63dBc}
\]

From the noise power \(N\) we can calculate the RMS phase jitter value in radians using the following formula:

\[
\text{RMS Phase Jitter (radians)} = 2\sqrt{10^{N/10}}
\]

\[
\text{RMS Phase Jitter} = 2\sqrt{10^{-63/10}} = 0.001416 \text{ radians}
\]

The jitter value in radians can be converted to RMS jitter in time units of seconds:

\[
\text{RMS Jitter (secs)} = \frac{\text{jitter (radians)}}{2 \times \pi \times f}
\]

In this example, the oscillator frequency \(f = 311\text{MHz}\). So we get:

\[
\text{RMS Jitter} = \frac{0.001416}{2 \times \pi \times 311\text{MHz}} = 0.72 \text{ pico seconds RMS}
\]

When jitter is derived from phase noise plots, the sideband frequency interval over which it is calculated must always be specified.

Summary

This note has described the following:

- How RMS jitter (time domain) is quantified based on standard deviation of a Gaussian distribution.
- How peak-to-peak jitter (time domain) can be predicted from the RMS jitter using multipliers related to BER requirements.
- How RMS phase jitter in frequency domain is calculated using phase noise plots.

The following appendix gives examples of how to check jitter specifications and system requirements.
Appendix: Checking Jitter Specifications and System Requirements

Example 1: Based on the FPGA specifications below, is it possible to use the clock output from the StratixV to clock a Broadcom 1GE Phy?

Phy clock input specified at 1.5ps RMS max.

<table>
<thead>
<tr>
<th>Altera FPGA</th>
<th>PLL Type</th>
<th>Input Frequency</th>
<th>PLL BW</th>
<th>Output Frequency Range</th>
<th>Jitter</th>
</tr>
</thead>
<tbody>
<tr>
<td>StratixV E, GX, GS, GT</td>
<td>Fractional or Integer VCO 600-1300/1600MHz (speed grade dependent)</td>
<td>Min 5 MHz to 800 MHz (speed grade dependent)</td>
<td>From 300KHz to 4MHz</td>
<td>Max from 553 MHz to 800 MHz (speed grade dependent)</td>
<td>Max from Dedicated Clock Output: 175ps to 250ps max pk-pk jitter Max from GPIO: 600ps max pk-pk jitter</td>
</tr>
</tbody>
</table>

The BER requirement for 1GE (gigabit Ethernet) is $1 \times 10^{-12}$. From Table 1 previously (BER and RMS Multiplier N), pk-pk jitter is approximately equal to 14 x RMS jitter. Therefore we have:

StratixV jitter (min) = 175/14 = 12.5ps RMS

StratixV jitter (max) = 250/14 = 17.9ps RMS

As can be seen this is much larger than can be tolerated by the Broadcom Phy, and another clock source will be required.

Example 2: Can the StratixV clocks be used to provide timing for PCIe Gen2 systems?

PCle Gen2 Clock Requirements

<table>
<thead>
<tr>
<th>Transmitter REF CLOCK Phase Noise (622MHz)</th>
<th>100Hz</th>
<th>1kHz</th>
<th>10kHz</th>
<th>100kHz</th>
<th>≥1MHz</th>
<th>10kHz to 1.5MHz (PCIe)</th>
</tr>
</thead>
<tbody>
<tr>
<td>—</td>
<td>—</td>
<td>—</td>
<td>-70</td>
<td>—</td>
<td>—</td>
<td>—</td>
</tr>
<tr>
<td>—</td>
<td>—</td>
<td>—</td>
<td>-90</td>
<td>—</td>
<td>—</td>
<td>—</td>
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<tr>
<td>—</td>
<td>—</td>
<td>—</td>
<td>-100</td>
<td>—</td>
<td>—</td>
<td>-100</td>
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<tr>
<td>—</td>
<td>—</td>
<td>—</td>
<td>-110</td>
<td>—</td>
<td>—</td>
<td>-110</td>
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<tr>
<td>—</td>
<td>—</td>
<td>—</td>
<td>-120</td>
<td>—</td>
<td>—</td>
<td>-120</td>
</tr>
<tr>
<td>—</td>
<td>—</td>
<td>—</td>
<td>—</td>
<td>—</td>
<td>—</td>
<td>3</td>
</tr>
</tbody>
</table>

• PCIe Gen2 100MHz reference clock is 3ps RMS jitter max from 10kHz to 1.5MHz.
• The 622.08MHz TX reference clock is 1.44ps RMS jitter max from 100Hz to 1MHz.

From the previous example, best case, the internal PLLs of the StratixV generate a clock with max RMS jitter of 12.5ps.

As the reference clocks of the StratixV transceivers require 1.44ps or 3ps in the above examples, the internal StratixV PLLs are not able to clock them.

Sources

Figure 4 and Figure 5 are from an internal IDT training presentation Jitter - Theory and Measurements by Alberto Urbieta

Figure 7 is from an IDT white paper RMS Phase Jitter by Alberto Urbieta

Figure 8 is from the paper titled Phase Noise and Jitter Characterization in Oscillator Applications by Thomas Fischer at Texas Instruments
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